

First workshop “Electronic Calibration Units” and European ANAMET meeting

On the 5th December 2013 we held the first workshop associated with the HF-Circuits EMRP project.

The first session of the workshop was focused on results from the research on electronic calibration units. The focus was on the draft of a methodology for evaluating drift in electronic calibration units and some preliminary results on using the methodology. We also had a discussion with the participants about the draft and the results.

The second session was held in the spirit of the old ANAMET group hosted at NPL for many years. This session included a few presentations from the participants of the EMRP project and some from the wider community.

This workshop will circulate between the participants of the project and happen twice a year.

We had 28 participants from 10 countries on site. We even had a participant from New Zealand and one additional remote presenter from USA.



Programme

- | | | |
|--------------------------|---|--|
| 1. | Welcome | Jörgen Stenarson, SP, Sweden |
| Project workshop session | | |
| 2. | European Research Project - Metrology for new electrical measurement quantities in high-frequency circuits: an overview of activities | Nick Ridler, NPL, UK |
| 3. | Uncertainty in two-port electronic calibration units: A progress report on the uncertainty model | Jörgen Stenarson, SP, Sweden
Chris Eiø, NPL, UK |
| 4. | ECU Test Methods | Markus Zeier, METAS, Switzerland |
| 5. | Electronic Calibration Units - Temperature Stability Tests | Rolf Judaschke, PTB, Germany |
| 6. | ECU Stability Short 1st Data Set METAS | Peter Huerlimann, METAS, Switzerland |
| 7. | Discussion/questions to start the discussions | Jörgen Stenarson, SP, Sweden |

Afternoon ANAMET session

- | | | |
|-----|--|--|
| 8. | Investigating connection repeatability of waveguide devices at frequencies from 750 GHz to 1.1 THz | Nick Ridler, NPL, UK |
| 9. | Single Flange 2-port Design For THz Integrated Circuit S-parameter Characterization | Johanna Hanning, Chalmers University of Technology, Sweden |
| 10. | An automated system for investigation of the impact of cable flexure on VNA measurements | Faisal Mubarak, VSL, The Netherlands |
| 11. | Test Port Cable life cycle tests | Joachim Schubert, Rosenberger |
| 12. | On evaluating the uncertainty of VNA self-calibration procedures | Blair Hall, Measurement Standards Laboratory, New Zealand |
| 13. | ECAL - Design and Test Overview | Ken Wong, Agilent Technologies, USA |